

**Search Notes**

Application/Control No.

10/563,002

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

FREDERIKSEN ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	10	1/11/2008	HN
330	207A	1/11/2008	HN
330	251	1/11/2008	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
US-PGPUB		1/11/2008	HN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	1/9/2008	HN